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Complete if Known Substitute for form 1449/PTO Application Number 10/573,463-Conf. #9267 **INFORMATION DISCLOSURE** Filing Date December 1, 2006 STATEMENT BY APPLICANT First Named Inventor Eric Pascal Feltin Art Unit 2812 2823 (Use as many sheets as necessary) Not Yet Assigned Examiner Name 1 **REGIM 3.3-089** Sheet of 1 Attorney Docket Number

			U.S. PA	TENT DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

	FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	٦٩		

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		NON PATENT LITERATURE DOCUMENTS	
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/AS	CA	Frayssinet, Beaumont, Faurie, Gibart, Makkai, Lefebvre and Valvin, "Micro Epitaxial Lateral Overgrowth of GaN/sapphire by Metal Organic Vapour Phase Epitaxy", MRS Internet J. Nitride Semicond. Res. 7, 8 (2002), pages 1-7.	

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Examiner Signature	/Ankush Singal/	Date Con	te nsidered	05/18/2007	
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Applicant's unique citation designation number (optional). Applicant is to place a check mark here if English language Translation is attached.

PTO/SB/08A/B (08-08)
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		FOREIC	ON PATENT	DOCUMENTS		
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/AS/	CA	Beaumont B., Vennegues P., Gibart P., "Epitaxial Overgrowth of GaN", Phys. Stat. sol. (b) 227, No. 1, pgs. 1-43, 2001.					
/AS/	СВ	Lahreche, Vennegues, Beaumont and Gibart, "Growth of high-quality GaN by low pressure metal-organic vapor phase epitaxy (LP-MOVPE) from 3D islands and lateral overgrowth", Journal of Crystal Growth 205, 245 (1999).					
/AS/	СС	Mathis et al., "Modeling of threading dislocation reduction in growing GaN layers", Journal of Crystal Growth, 231, pgs 371-390, (2001).					

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Substitut	e for form 1449/P	то			Complete if Known
				Application Number	10/573,463
INF	ORMATI	ON DISC	LOSURE	Filing Date	March 24, 2006
STA	TEMEN	T BY AP	PLICANT	First Named Inventor	Eric Pascal Feltin
				Art Unit	NA 9 2823
	(Use as man	y sheets as nec	essary)	Examiner Name	Not Yet Assigned Some
Sheet	1	of	1	Attorney Docket Number	REGIM 3.3-089

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Examiner Cite Initials* No.1		Number-Kind Code ² (#known) MM-DD-YYYY		Applicant of Cited Document	Relevant Passages or Relevant Figures Appear				
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			Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)		Applicant of Cited Document	or Relevant Figures Appear	*
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		BB	WO-96/41906-A	12-27-1996	Advanced Tech Materials		V
	$\overline{\cdot}$	вс	EP-1 245 702-A	10-02-2002	Hitachi Cable, Ltd.		
	7	BD	EP-1 041 610-A1 //	10-04-2002	Sumitomo Electric Industries		1
/AS	3/	BE	WO-03/062507-A	07-31-2003	S.O.I.Tec Silicon Insulator Technologies		V

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